

### 1 Megabit Static RAM 256K x 4-Bit with Fast Sequential Access Mode

PSM44028S  
PSM44028L

#### Features

- MIPS R4000 support
- High speed access times  
Com'l: 20, 25, and 35ns  
Mil : 20, 25, 35, and 45ns
- Low power operation
  - PSM44028S  
Active: 400mW (typ.)  
Standby: 150 mW (typ.)
  - PSM44028L  
Active: 350mW (typ.)  
Standby: 100 mW (typ.)
- Single +5V ( $\pm 10\%$ ) power supply
- TTL compatible inputs and outputs
- Military product MIL-STD-883, Rev. C
- Packages
  - Sidebraze DIP(400 mil) - TC,
  - Plastic SOJ(300 mil) - TSO,
  - Plastic SOJ(400 mil) - SO

#### Description

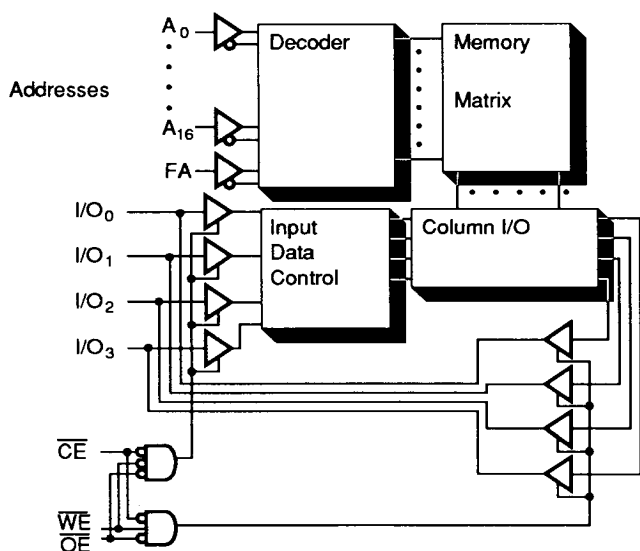
The PSM44028 is a high performance CMOS static RAM organized as 262144 x 4 bits. This product is produced in Paradigm's proprietary CMOS technology which offers the designer the highest speed parts. Writing to this device is accomplished when the write enable ( $\overline{WE}$ ) and the chip enable ( $\overline{CE}$ ) inputs are both LOW. Reading is accomplished when  $\overline{WE}$  remains HIGH and  $\overline{CE}$  and  $\overline{OE}$  go to LOW. The PSM44028 has a feature which allows for a very fast sequential read. This mode will increase the efficiency of servicing primary cache misses when designing with the MIPS R4000 RISC processors.

The PSM44028 operates from a single +5V power supply and all the inputs and outputs are fully TTL compatible. The PSM44028 comes in two versions, the standard power version PSM44028S and a low power version the PSM44028L. The two versions are functionally the same and only differ in their power consumption.

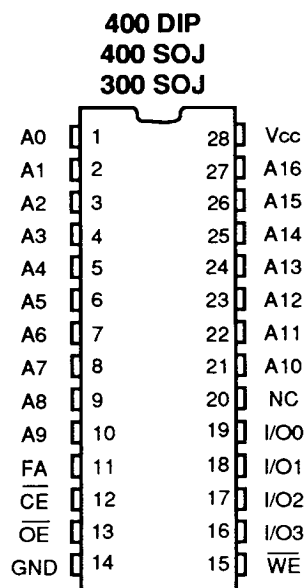
The PSM44028 is available in a 28-pin 400 mil DIP. The PSM44028 will also be available in a 28-pin 400 mil and 300 mil SOJ for surface mount applications.

Military grade product is manufactured in compliance with the latest revision of MIL-STD-883, Rev. C, making the PSM44028 ideally suited for military temperature applications.

#### Functional Block Diagram

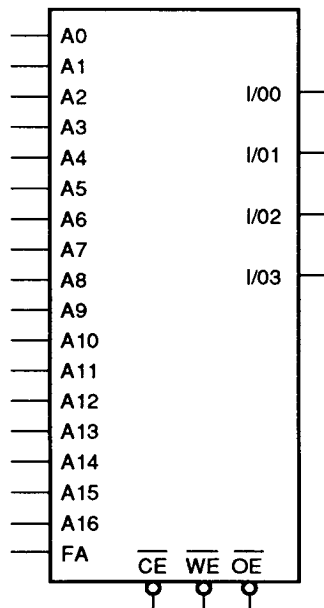


#### Pin Configuration



# PSM44028S PSM44028L

## Logic Symbol



## Recommended Operating Temperature and Supply Voltage

Grade	Ambient Temperature	GND	V <sub>CC</sub>
Military	-55°C to +125°C	0V	5.0V ± 10%
Commercial	0°C to +70°C	0V	5.0V ± 10%

## Recommended DC Operating Conditions

Symbol	Parameter	Min.	Typ.	Max.	Unit
V <sub>CC</sub>	Supply Voltage	4.5	5.0	5.5	V
GND	Supply Voltage	0	0	0	V
V <sub>IH</sub>	Input High Voltage	2.2	—	6.0	V
V <sub>IL</sub>	Input Low Voltage	-0.5 <sup>(1)</sup>	—	0.8	V

### NOTE:

1. V<sub>IL</sub> (min) = -3.0V for pulse width less than 20ns.

## Truth Table<sup>(1)</sup>

OE	WE	CE	I/O	MODE
X	X	H	Hi-Z	Standby
L	H	L	D <sub>OUT</sub>	Read
X	L	L	D <sub>IN</sub>	Write
H	H	L	Hi-Z	Output Disable

### NOTE:

1. H = V<sub>IH</sub>, L = V<sub>IL</sub>, X = DON'T CARE.

## Pin Description

Symbol	Description
A0–A16	Address lines
FA	Fast sequence address
I/O–I/O3	Input/output
OE	Output enable
CE	Chip enable
V <sub>CC</sub>	+5V power supply
GND	Ground
WE	Write enable

**PSM44028S**  
**PSM44028L**

**Electrical Characteristics**  $V_{CC} = 5.0V \pm 10\%$

Symbol	Parameter	Test Conditions	PSM44028S		PSM44028L		Unit
			Min.	Max.	Min.	Max.	
$ I_{LI} $	Input Leakage Current	$V_{CC} = \text{Max.}, V_{IN} = \text{GND to } V_{CC}$	MIL. Com'l	— 10 5	— 5	— 5 2	$\mu\text{A}$
$ I_{LO} $	Output Leakage Current	$V_{CC} = \text{Max.}$ $\overline{CE} = V_{IH}, V_{OUT} = \text{GND to } V_{CC}$	MIL. Com'l	— 10 5	— 5	— 5 2	$\mu\text{A}$
$V_{OL}$	Output Low Voltage	$I_{OL} = 8\text{mA}, V_{CC} = \text{Min.}$	—	0.4	—	0.4	V
		$I_{OL} = 10\text{mA}, V_{CC} = \text{Min.}$	—	0.5	—	0.5	V
$V_{OH}$	Output High Voltage	$I_{OH} = -4\text{mA}, V_{CC} = \text{Min.}$	2.4	—	2.4	—	V

**DC Electrical Characteristics<sup>(1)</sup>** ( $V_{CC} = 5.0V \pm 10\%, V_{LC} \leq 0.2V, V_{HC} \geq V_{CC} - 0.2$ )

Symbol	Parameter	Power	Function	20,		25,		35, 45 <sup>(3)</sup> ns		Unit
				Com'l.	Mil.	Com'l.	Mil.	Com'l.	Mil.	
$I_{CC}$	Dynamic Operating Current $\overline{CE} = V_{IL}$	S	Read	170	180	160	170	150	160	mA
		L	Read	170	180	160	170	150	160	mA
$I_{SB}$	Standby Power Supply Current (TTL Level)	S	—	50	50	40	40	30	30	mA
		L	—	40	40	35	35	30	30	mA
$I_{SB1}$	Full Standby Power Supply Current (CMOS Level)	S	—	10	10	10	10	10	10	mA
		L	—	5	5	5	5	5	5	mA

**NOTES:**

- All values are maximum guaranteed values.
- At  $f = f_{MAX}$  address and data inputs are cycling at the maximum frequency of read cycles of  $1/t_{RC}$ .  $f = 0$  means no input lines change.
- The 45ns speed grade is available in Military grade product only.

**Capacitance<sup>(1)</sup>** ( $T_A = +25^\circ\text{C}, f = 1.0\text{MHz}$ )

Symbol	Parameter	Conditions	Max.	Unit
$C_{IN}$	Input Capacitance	$V_{IN} = 0V$	8	pF
$C_{OUT}$	Output Capacitance	$V_{OUT} = 0V$	8	pF

**NOTE:**

- This parameter is determined by device characterization but is not production tested.

### AC Test Conditions

Input pulse levels ..... GND to 3.0V  
 Input rise and fall times ..... 5ns  
 Input timing reference levels ..... 1.5V  
 Output reference levels ..... 1.5V  
 Output load ..... See figures 1 and 2

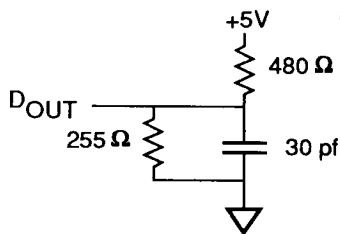


Fig. 1 Output Load Equivalent

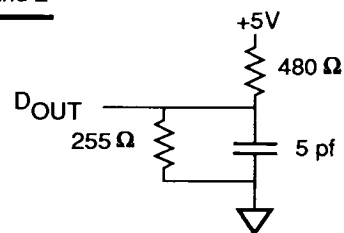
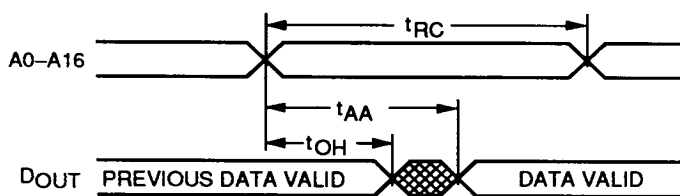
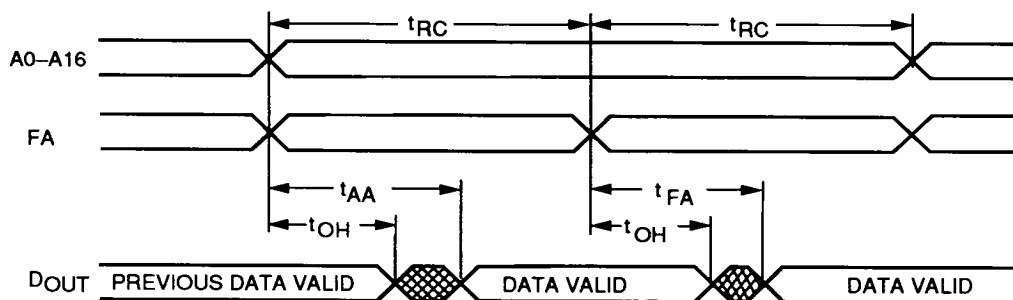


Fig. 2 Output Load Equivalent  
(for  $t_{LZCE}$ ,  $t_{HZCE}$ ,  $t_{LZWE}$ ,  $t_{HZWE}$ ,  
 $t_{LZOE}$ ,  $t_{HZOE}$ )

### Read Cycle No. 1(6, 7)

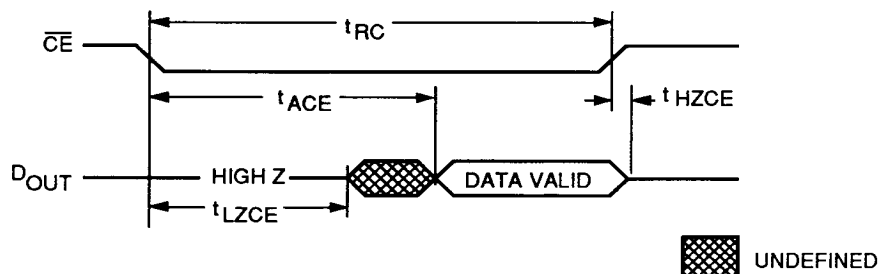


### Fast Sequential Read Cycle(6, 7)



**PSM44028S**  
**PSM44028L**

**Read Cycle No. 3(3, 6, 8)**

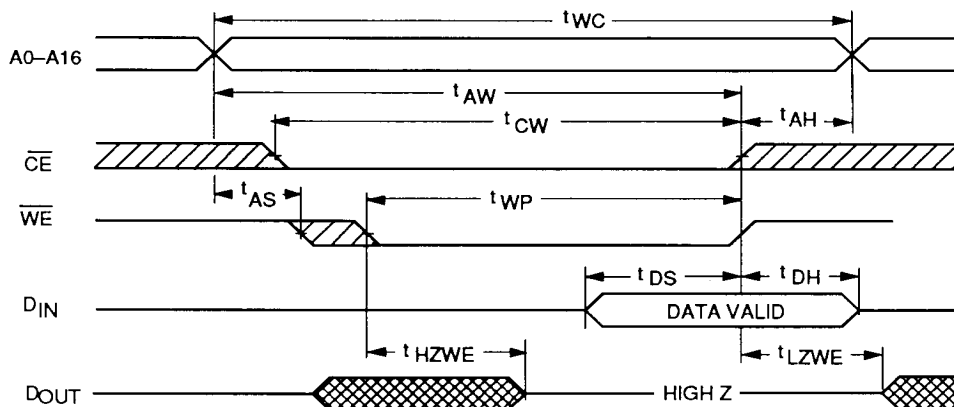


**AC Electrical Characteristics**  $V_{CC} = 5V \pm 10\%$ , All Temperature Ranges

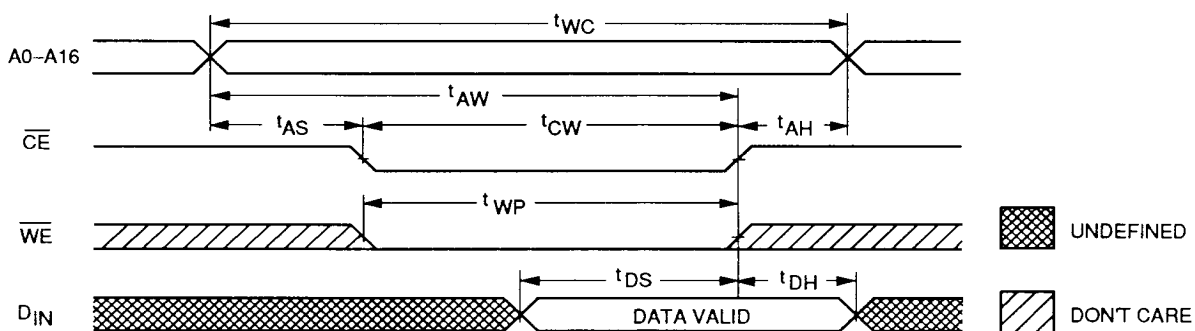
Description	Sym	-20		-25		-35		-45 <sup>(1)</sup>		Units
		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
READ Cycle	$t_{RC}$	20		25		35		45		ns
Address access time	$t_{AA}$		20		25		35		45	ns
Chip enable access time	$t_{ACE}$		20		25		35		45	ns
Output hold from address change	$t_{OH}$	0		0		0		0		ns
Chip enable to output in low Z <sup>(4)</sup>	$t_{LZCE}$	5		5		5		5		ns
Chip disable to output in high Z <sup>(2, 3, 4)</sup>	$t_{HZCE}$		10		15		20		20	ns
Chip enable to power up time <sup>(4)</sup>	$t_{PU}$	0		0		0		0		ns
Chip disable to power downtime <sup>(4)</sup>	$t_{PD}$		20		25		30		40	ns
Output enable access time	$t_{AOE}$		10		12		15		20	ns
Output Enable to output in low Z <sup>(4)</sup>	$t_{LZOE}$	0		0		0		0		ns
Output disable to output in high Z <sup>(2, 4)</sup>	$t_{HZOE}$		8		10		10		15	ns
Fast Address Access Time	$t_{FA}$		5		6		7		10	ns

Notes referenced are after Data Retention Table.

Write Cycle No. 1 (Write Enable Controlled)



Write Cycle No. 2 (Chip Enable Controlled)

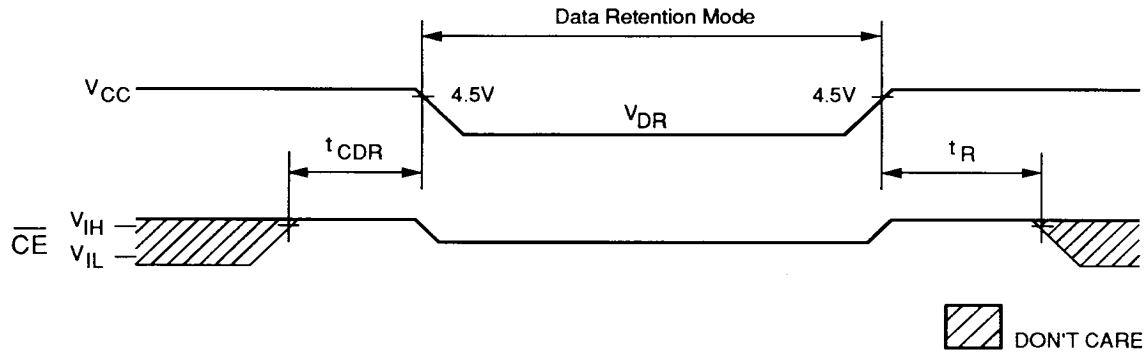


AC Electrical Characteristics V<sub>CC</sub> = 5V ± 10%, All Temperature Ranges

Description	Sym	-20		-25		-35		-45 <sup>(1)</sup>		Units
		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
WRITE Cycle										
WRITE cycle time	t <sub>WC</sub>	20		25		35		45		ns
Chip enable to end of write	t <sub>CW</sub>	17		20		30		40		ns
Address Valid to end of write	t <sub>AW</sub>	17		20		30		40		ns
Address set-up time	t <sub>AS</sub>	0		0		0		0		ns
Address hold from end of write	t <sub>AH</sub>	0		0		0		0		ns
Write pulse width	t <sub>WP</sub>	17		17		25		30		ns
Data set-up time	t <sub>DS</sub>	12		12		15		20		ns
Data hold time	t <sub>DH</sub>	0		0		0		0		ns
Write disable to output in low Z <sup>(4)</sup>	t <sub>LZWE</sub>	0		0		0		0		ns
Write enable to output in high Z <sup>(2, 4)</sup>	t <sub>HZWE</sub>		8		10		15		20	ns

PSM44028S  
PSM44028L

Low  $V_{CC}$  Data Retention Waveform



Data Retention Electrical Characteristics (L Version Only)

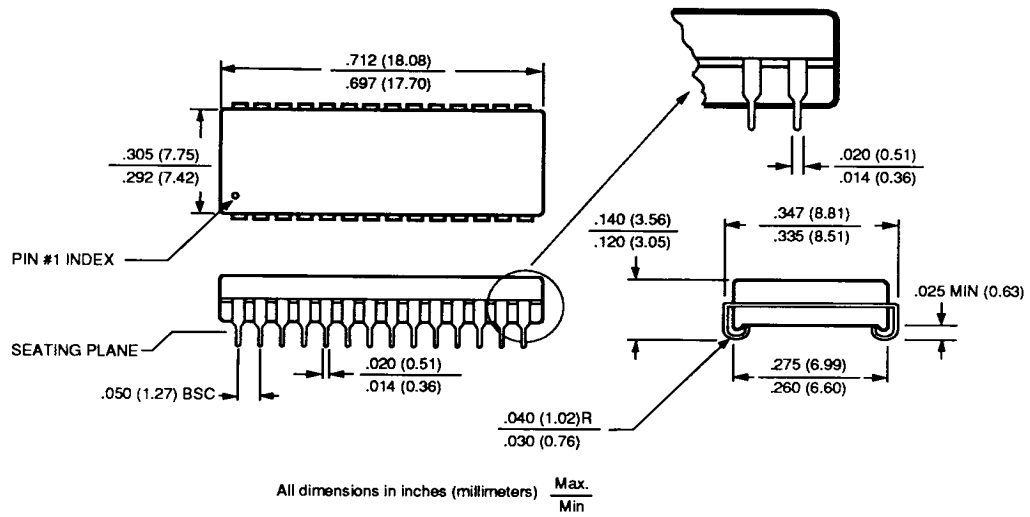
Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Unit
$V_{DR}$	$V_{CC}$ for Retention Data		2	—	—	V
$I_{CCDR}$	Data Retention Current	$\overline{CE} \geq V_{CC} - 0.2V$ $V_{CC} = 2V$	—	95	500	$\mu A$
		$V_{IN} \geq V_{CC} - 0.2V$ $V_{CC} = 3V$ or $\leq 0.2V$	—	350	750	$\mu A$
$t_{CDR}$	Chip Deselect to Data Retention Time		0	—	—	ns
$t_R^{(4)}$	Operation Recovery Time		$t_{RC}^{(5)}$	—	—	ns

NOTES: (For 3 previous Electrical Characteristics tables)

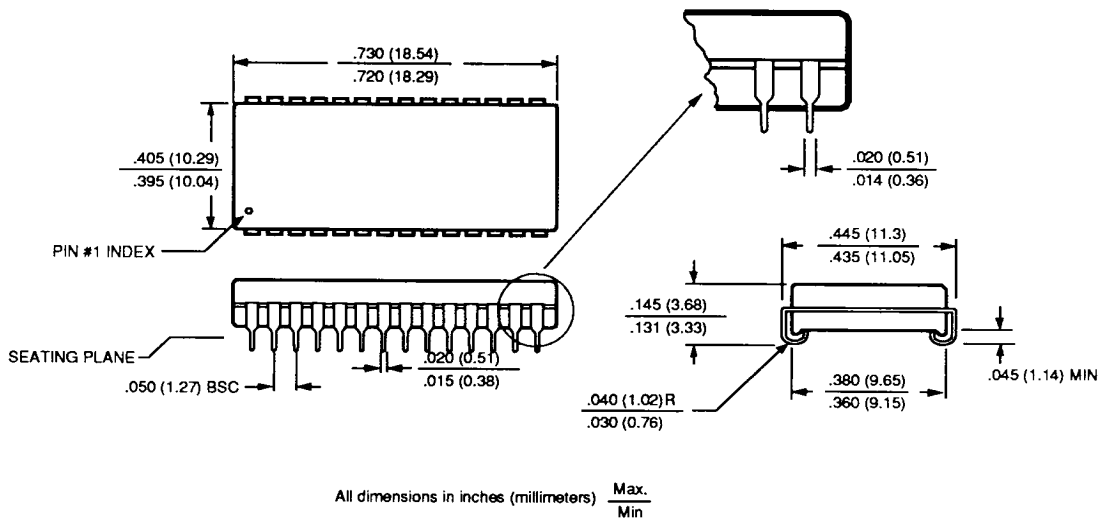
- 55°C to +125°C temperature range only.
- $t_{HZCE}$  and  $t_{HZWE}$  are tested with  $C_L = 5pF$  as shown in Fig. #2. Transition is measured  $\pm 200mV$  from steady state voltage.
- At any given temperature and voltage condition,  $t_{HZCE}$  is less than  $t_{LZCE}$ .
- This parameter is sampled.
- $t_{RC}$  = Read cycle time.
- $\overline{WE}$  is high for a READ cycle.
- The device is continuously selected. All the Chip Enables are held in their active state.
- The address is valid prior to or coincident with the latest occurring Chip Enable.

**PSM44028S**  
**PSM44028L**

**28 pin Plastic SOJ 300 mil**



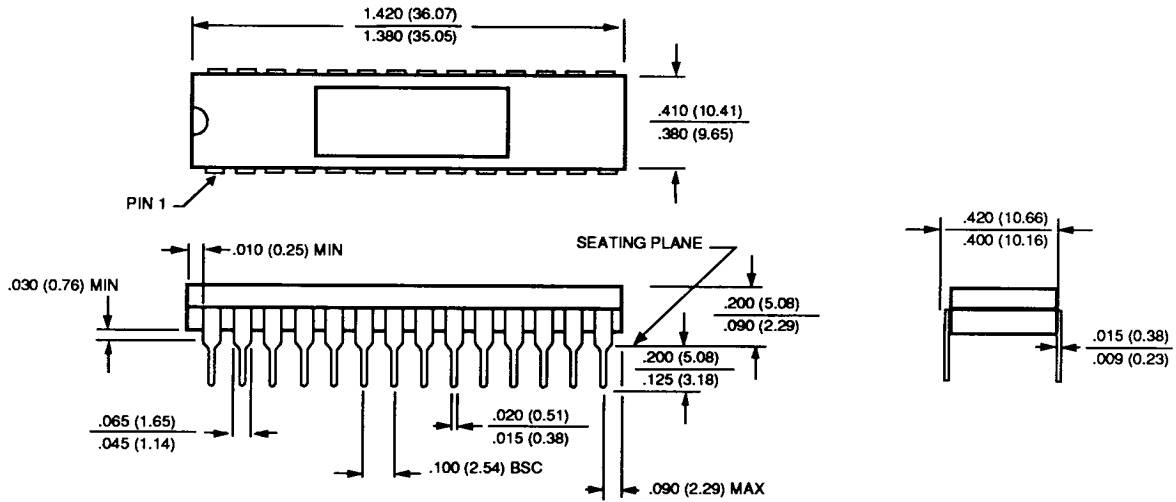
**28 pin Plastic SOJ 400 mil**





**PSM44028S**  
**PSM44028L**

**28 pin 400 mil Sidebrazed DIP**



All dimensions in inches (mm)  $\frac{\text{Max.}}{\text{Min.}}$

**PSM44028S**  
**PSM44028L**

**Ordering Information**

<b>PSM</b>	<b>XXXXX</b> Device Type	<b>A</b> Power	<b>XX</b> Speed	<b>A</b> Package	<b>A</b> Process / Temperature Range
					Blank Commercial (0° to +70°C)
					M Mil. Temp. Only (-55°C to +125°C)
					B Military (-55°C to +125°C) Compliant to MIL-STD 883
					TC 400 mil Sidebrazed Dip
					TSO 300 mil Plastic SOJ
					SO 400 mil Plastic SOJ
					20
					25
					35
					45 Military Only
					S Standard Power
					L Low Power
					44028 1 Meg (256K x 4) Static RAM with Fast Sequential Access Mode

**PSM44028S**  
**PSM44028L**

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